

N-Channel Enhancement Mode Power MOSFET

Description

The HM8205Q uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

V_{DS} =20V,I_D =10A

 $R_{DS(ON)}$ < 11m Ω @ V_{GS} =4.5V

 $R_{DS(ON)}$ < 11.5m Ω @ V_{GS} =4V

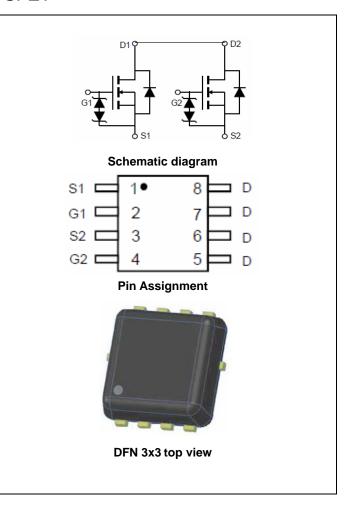
 $R_{DS(ON)} < 12.5 \text{m}\Omega$ @ $V_{GS} = 3.1 \text{V}$

 $R_{DS(ON)}$ < 15.5m Ω @ V_{GS} =2.5V

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- 2.5V Drive
- Common-drain type

Application

- Battery protection switch
- Mobile device battery charging and discharging



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM8205Q	HM8205Q	DFN 3x3	-	-	-

Absolute Maximum Ratings (T_C=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	20	V
Gate-Source Voltage	V _G S	±12	V
Drain Current-Continuous	I _D	10	А
Pulsed Drain Current	I _{DM}	32	Α
Maximum Power Dissipation	P _D	1.5	W
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}$ C

Thermal Characteristic

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{ heta JA}$	83	°C/W



Electrical Characteristics (TC=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics							
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	20		-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V,V _{GS} =0V	-	-	1	μA	
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±10V,V _{DS} =0V	-	-	±10	μA	
On Characteristics (Note 3)							
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	0.5	0.7	1	V	
		V_{GS} =4.5V, I_D =10A	-	7.2	11		
Drain Source On State Besistance	R _{DS(ON)}	V _{GS} =4 V, I _D =5A	-	7.4	11.5		
Drain-Source On-State Resistance		V _{GS} =3.1V, I _D =5A		7.8	12.5	- mΩ	
		V _{GS} =2.5V, I _D =2.5A		8.6	15.5		
Forward Transconductance	g FS	V _{DS} =10V,I _D =5A	5	-	-	S	
Dynamic Characteristics (Note4)							
Input Capacitance	C _{lss}	\\ 40\\\\ 0\\	-	1255	-	PF	
Output Capacitance	C _{oss}	V_{DS} =10V, V_{GS} =0V, F=1.0MHz	-	220	-	PF	
Reverse Transfer Capacitance	C _{rss}	F=1.UIVIHZ	-	168	-	PF	
Switching Characteristics (Note 4)			•				
Turn-on Delay Time	t _{d(on)}		-	300	-	nS	
Turn-on Rise Time	t _r	V_{DD} =10 V , I_{D} =5 A	-	1000	-	nS	
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10 V , R_{GEN} =50 Ω	-	4000	-	nS	
Turn-Off Fall Time	t _f		-	2500	-	nS	
Total Gate Charge	Qg	V 40VI 40A	-	29	-	nC	
Gate-Source Charge	Q_{gs}	V _{DS} =10V,I _D =10A,	-	5.2	-	nC	
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	6.3	-	nC	
Drain-Source Diode Characteristics			•				
Diode Forward Voltage (Note 3)	V_{SD}	V _{GS} =0V,I _S =10A	-	0.85	1.2	V	
Diode Forward Current (Note 2)	Is		-	-	10	Α	

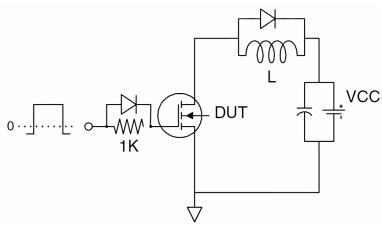
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- **4.** Guaranteed by design, not subject to production

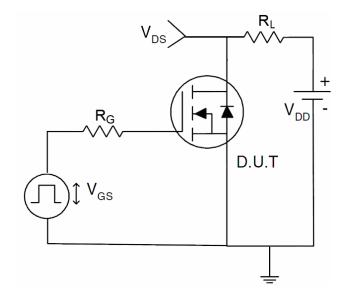


Test Circuit

1) Gate Charge Test Circuit

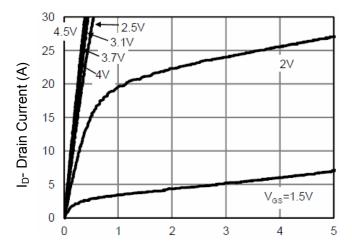


2) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)



Vds Drain-Source Voltage (V)

Figure 1 Output Characteristics

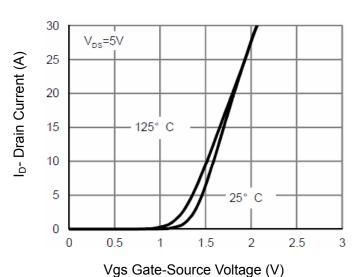


Figure 2 Transfer Characteristics

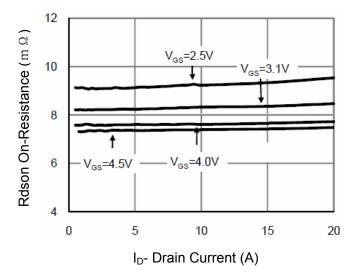


Figure 3 Rdson- Drain Current

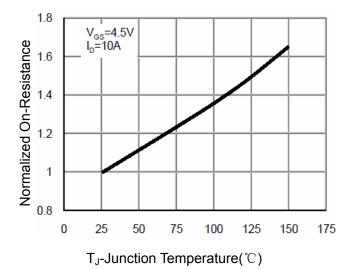


Figure 4 Rdson-Junction Temperature

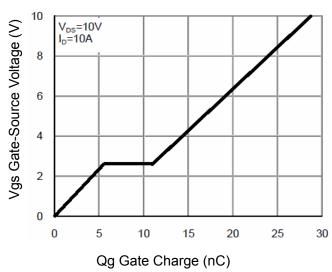


Figure 5 Gate Charge

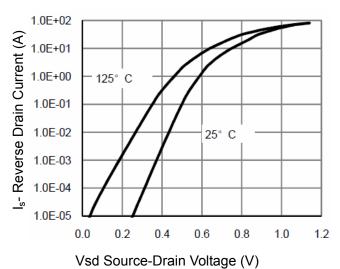


Figure 6 Source- Drain Diode Forward



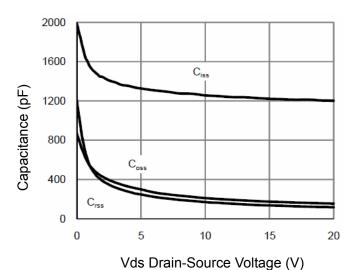


Figure 7 Capacitance vs Vds

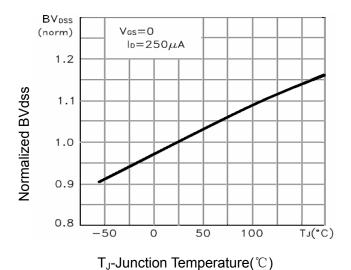


Figure 9 BV_{DSS} vs Junction Temperature

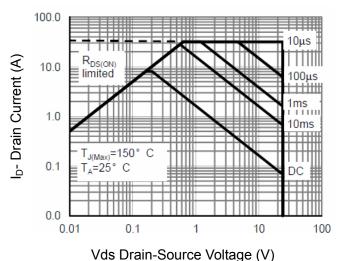
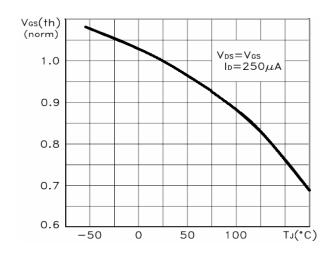
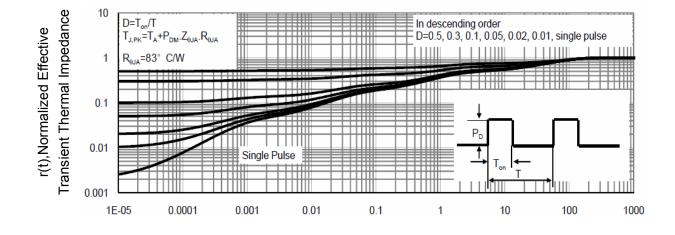


Figure 8 Safe Operation Area



 $\label{eq:TJ-Junction} T_{J}-Junction Temperature($^{\circ}$C)$$ $Figure 10 V_{GS(th)} vs Junction Temperature$

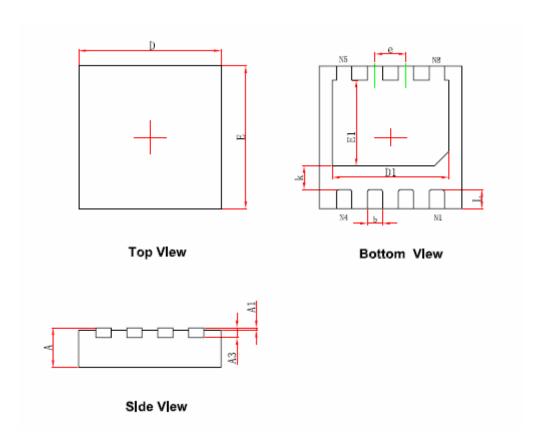


Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance



DFN3X3 EP Package Information



Cymah al	Dimensions I	n Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	0.700/0.800	0.800/0.900	0.028/0.031	0.031/0.035	
A1	0.000	0.050	0.000	0.002	
A3	0.203REF.		0.008REF.		
D	2.924	3.076	0.115	0.121	
E	2.924	3.076	0.115	0.121	
D1	2.350	2.550	0.093	0.100	
E1	1.700	1.900	0.067	0.075	
k	0.450	0.550	0.018	0.022	
b	0.270	0.370	0.011	0.015	
e	0.650TYP.		0.026TYP.		
L	0.324	0.476 0.013		0.019	



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